

IEEE Standard for Relays and Relay Systems Associated with Electric Power Apparatus

IEEE Power Engineering Society

Sponsored by the Power System Relaying Committee

MT067

(Revision of IEEE Std C37.90-1989)

IEEE Standard for Relays and Relay Systems Associated with Electric Power Apparatus

Sponsor

Power System Relaying Committee of the IEEE Power Engineering Society

Approved 22 September 2005 Reaffirmed 31 March 2011

IEEE-SA Standards Board

Approved 23 May 2012

American National Standards Institute

Abstract: Service conditions, electrical ratings, thermal ratings, and testing requirements are defined for relays and relay systems used to protect and control power apparatus. This standard establishes a common reproducible basis for designing and evaluating relays and relay systems. **Keywords:** ac component in dc, contact rating, current range, derating, dielectric test, humidity, impulse test, insulation test, power apparatus, protection relay, temperature range, temperature rise, voltage range

The Institute of Electrical and Electronics Engineers, Inc. 3 Park Avenue, New York, NY 10016-5997, USA

Copyright © 2006 by the Institute of Electrical and Electronics Engineers, Inc. All rights reserved. Published 31 January 2006. Printed in the United States of America.

IEEE is a registered trademark in the U.S. Patent & Trademark Office, owned by the Institute of Electrical and Electronics Engineers, Incorporated.

Print: ISBN 0-7381-4818-0 SH95381 PDF: ISBN 0-7381-4819-9 SS95381

No part of this publication may be reproduced in any form, in an electronic retrieval system or otherwise, without the prior written permission of the publisher.

IEEE Standards documents are developed within the IEEE Societies and the Standards Coordinating Committees of the IEEE Standards Association (IEEE-SA) Standards Board. The IEEE develops its standards through a consensus development process, approved by the American National Standards Institute, which brings together volunteers representing varied viewpoints and interests to achieve the final product. Volunteers are not necessarily members of the Institute and serve without compensation. While the IEEE administers the process and establishes rules to promote fairness in the consensus development process, the IEEE does not independently evaluate, test, or verify the accuracy of any of the information contained in its standards.

Use of an IEEE Standard is wholly voluntary. The IEEE disclaims liability for any personal injury, property or other damage, of any nature whatsoever, whether special, indirect, consequential, or compensatory, directly or indirectly resulting from the publication, use of, or reliance upon this, or any other IEEE Standard document.

The IEEE does not warrant or represent the accuracy or content of the material contained herein, and expressly disclaims any express or implied warranty, including any implied warranty of merchantability or fitness for a specific purpose, or that the use of the material contained herein is free from patent infringement. IEEE Standards documents are supplied "AS IS."

The existence of an IEEE Standard does not imply that there are no other ways to produce, test, measure, purchase, market, or provide other goods and services related to the scope of the IEEE Standard. Furthermore, the viewpoint expressed at the time a standard is approved and issued is subject to change brought about through developments in the state of the art and comments received from users of the standard. Every IEEE Standard is subjected to review at least every five years for revision or reaffirmation. When a document is more than five years old and has not been reaffirmed, it is reasonable to conclude that its contents, although still of some value, do not wholly reflect the present state of the art. Users are cautioned to check to determine that they have the latest edition of any IEEE Standard.

In publishing and making this document available, the IEEE is not suggesting or rendering professional or other services for, or on behalf of, any person or entity. Nor is the IEEE undertaking to perform any duty owed by any other person or entity to another. Any person utilizing this, and any other IEEE Standards document, should rely upon the advice of a competent professional in determining the exercise of reasonable care in any given circumstances.

Interpretations: Occasionally questions may arise regarding the meaning of portions of standards as they relate to specific applications. When the need for interpretations is brought to the attention of IEEE, the Institute will initiate action to prepare appropriate responses. Since IEEE Standards represent a consensus of concerned interests, it is important to ensure that any interpretation has also received the concurrence of a balance of interests. For this reason, IEEE and the members of its societies and Standards Coordinating Committees are not able to provide an instant response to interpretation requests except in those cases where the matter has previously received formal consideration.

Comments for revision of IEEE Standards are welcome from any interested party, regardless of membership affiliation with IEEE. Suggestions for changes in documents should be in the form of a proposed change of text, together with appropriate supporting comments. Comments on standards and requests for interpretations should be addressed to:

Secretary, IEEE-SA Standards Board 445 Hoes Lane Piscataway, NJ 08854 USA

Note: Attention is called to the possibility that implementation of this standard may require use of subject matter covered by patent rights. By publication of this standard, no position is taken with respect to the existence or validity of any patent rights in connection therewith. The IEEE shall not be responsible for identifying patents for which a license may be required by an IEEE standard or for conducting inquiries into the legal validity or scope of those patents that are brought to its attention.

Authorization to photocopy portions of any individual standard for internal or personal use is granted by the Institute of Electrical and Electronics Engineers, Inc., provided that the appropriate fee is paid to Copyright Clearance Center. To arrange for payment of licensing fee, please contact Copyright Clearance Center, Customer Service, 222 Rosewood Drive, Danvers, MA 01923 USA; (978) 750-8400. Permission to photocopy portions of any individual standard for educational classroom use can also be obtained through the Copyright Clearance Center.

Introduction

This introduction is not part of IEEE Std C37.90-2005, IEEE Standard for Relays and Relay Systems Associated with Electric Power Apparatus.

This revision of IEEE Std C37.90 contains significant changes in content and organization so it will harmonize more closely with currently published IEC standards whenever possible. The standard has also been updated to include many changes to provide for a more effective document that is now representative of currently manufactured relay products used in the industry. The changes are as described in the following list.

- a) Clause 2, Normative references, has been added where required.
- b) Clause 3, Definitions, has been revised to provide for alphabetical classification by function.
- c) Clause 4, Service conditions, has been revised to provide categories for specific temperature ranges and differentiation of ambient and extreme temperature ranges. Relative humidity now specifies relay or relay systems. Other conditions have been changed to show numeric designations.
- d) Clause 5, Electrical ratings, specifies additional standard current and voltage ratings and notes, applicable to Table 3. Table 4 specifies additional maximum design voltages for dc control. Table 7 and Table 8 specify coil resistance/burden at ambient temperature 25 °C. A subclause has been added to address latching current requirements.
- e) Clause 6, Heating limits of temperature rise for coils, has been revised to add information on how the temperature rise of the coils is to be determined.
- f) Clause 7, Mechanical requirements, has been added to provide information on the mechanical durability of relays, plug-in feature requirements, and relay setting controls to harmonize with current IEC requirements.
- g) Clause 8, Insulation tests, was changed from Dielectric tests and now includes the requirement for an impulse voltage test as a design test. Table 9 and Figure 1 have been added to this clause.
- h) An annex of International Electrotechnical Commission (IEC) standards, relevant to IEEE Std C37.90, has been added to provide additional information for clarification and harmonization with IEC standards. In preparing this standard, consideration has been given to the work of other committees, and especially to international standards that have been published or that are under preparation by Technical Committee 95 of IEC.

Notice to users

Errata

Errata, if any, for this and all other standards can be accessed at the following URL: http://standards.ieee.org/reading/ieee/updates/errata/index.html. Users are encouraged to check this URL for errata periodically.

Interpretations

Current interpretations can be accessed at the following URL: http://standards.ieee.org/reading/ieee/interp/index.html.

Patents

Attention is called to the possibility that implementation of this standard may require use of subject matter covered by patent rights. By publication of this standard, no position is taken with respect to the existence or validity of any patent rights in connection therewith. The IEEE shall not be responsible for identifying patents or patent applications for which a license may be required to implement an IEEE standard or for conducting inquiries into the legal validity or scope of those patents that are brought to its attention.

Participants

At the time this standard was completed, the C37.90 Working Group had the following membership:

Mario Ranieri, Chair James Teague, Vice-Chair

Robert W. Beckwith

Thomas R. Beckwith

John J. Horwath

James D. Huddleston, III

William M. Strang

Jeffrey Burnworth

Gerald F. Johnson

John W. Chadwick, Jr.

Peter A. Kotos

John Tengdin

Clifford L. Downs

Michael J. McDonald

David Viers

The following members of the individual balloting committee voted on this standard. Balloters may have voted for approval, disapproval, or abstention.

Roger Hedding

Hanna Abdallah William Ackerman Steve Alexanderson Richard F. Angle Stan J. Arnot Munnu Bajpai George Bartok Robert W. Beckwith Robert Beresh Michael Bio Stuart Bouchev Gustavo Brunello Jeffrey Burnworth Mark Carpenter Carlos Castro John W. Chadwick, Jr. Tommy Cooper Ratan Das Ronald Daubert Byron Davenport Clifford L. Downs Paul Drum Walter Elmore Amir El-Sheikh James Evans Kenneth Fodero Marcel Fortin Trilok Garg Frank Gerleve Jeffrey G. Gilbert Mietek Glinkowski Russ Gonnam Robert Goodin

Stephen Grier

Erik Guillot

Jerry Hohn Edward Horgan Jr. John J. Horwath James D. Huddleston, III Chris Huntley David Jackson George Kalacherry Hermann Koch Joseph L Koepfinger Peter A. Kotos Terry Krummrey Luther Kurtz Marc Lacroix Carl LaPlace Stephen R. Lambert Roger Lawrence Jason Lin Albert Livshitz William Lowe Gregory Luri William Majeski Thomas McCaffrey John McDonald Michael J. McDonald Mark McGranaghan Michael Meisinger A. Meliopoulos Gary Michel Dean Miller Charles Mozina Bruce Muschlitz Anthony Napikoski T. W. Olsen Russell Patterson Carlos Peixoto

Robert Pettigrew Paul Pillitteri Mario Ranieri Roger Ray Charles Rogers James Ruggieri Mohindar S. Sachdev Miriam Sanders David Schempp Thomas Schossig Tony Seegers Tarlochan Sidhu H. Jin Sim Mark Simon Veselin Skendzic James Smith James Stoner William M. Strang Charles Sufana Robert J. Sullivan Malcolm Swanson Richard Taylor James Teague John Tengdin

Kostas Pervolarakis

Shanmugan Thamilarasan Demetrios Tziouvaras Eric Udren Charles Wagner

Charles Wagner Ronald Westfall Kenneth White Murty Yalla Donald W. Zipse When the IEEE-SA Standards Board approved this guide on 22 September 2005, it had the following membership:

Steve M. Mills, Chair Richard H. Hulett, Vice Chair Don Wright, Past Chair Judith Gorman, Secretary

Mark D. Bowman Dennis B. Brophy Joseph Bruder Richard Cox Bob Davis Julian Forster* Joanna N. Guenin Mark S. Halpin Raymond Hapeman William B. Hopf Lowell G. Johnson Herman Koch Joseph L. Koepfinger* David J. Law Daleep C. Mohla Paul Nikolich T. W. Olsen Glenn Parsons Ronald C. Petersen Gary S. Robinson Frank Stone Malcolm V. Thaden Richard L. Townsend Joe D. Watson Howard L. Wolfman

*Member Emeritus

Also included are the following nonvoting IEEE-SA Standards Board liaisons:

Satish K. Aggarwal, NRC Representative Richard DeBlasio, DOE Representative Alan H. Cookson, NIST Representative

Jennie Steinhagen
IEEE Standards Project Editor

Contents

1. Overview	1
1.1 Scope	1
1.2 Purpose	2
2. Normative references	2
3. Special terms	2
4. Service conditions	2
4.1 Usual service conditions	
4.2 Unusual service conditions	4
5. Electrical ratings	5
5.1 Standard current and voltage ratings for relays	5
5.2 Maximum design voltage and current for relays	
5.3 Allowable variations from rated voltage for voltage operated auxiliary relays	
5.4 Allowable variation from rated voltage and current for protective relays	
5.5 Allowable ac component in dc control voltage supply	
5.6 Short time thermal withstand	
5.7 Make, carry, and interrupt ratings for tripping output circuits	
5.8 Make, carry, and interrupt ratings for output circuits not rated for tripping	
5.9 Published data for auxiliary relays	
6. Heating limits of temperature rise for coils	12
7. Mechanical requirements	12
7.1 Mechanical durability of relay operation	12
7.2 Mechanical durability of plug-in relays	
7.3 Mechanical durability of relay setting controls	
7.4 Shock and vibration	
8. Insulation tests	13
8.1 General requirements	13
8.2 Dielectric power frequency tests	
8.3 Impulse voltage tests	
Anney A (informative) Applicable IEC standards	17

IEEE Standard for Relays and Relay Systems Associated with Electric Power Apparatus

1. Overview

This standard specifies standard service conditions, standard ratings, performance requirements, and testing requirements for relays and relay systems used to protect and control power apparatus. The standard establishes a common reproducible basis for designing and evaluating relay and relay systems. Annex A provides a cross-reference to the applicable IEC standards. Certain specific tests required for relays and relay systems are covered in separate IEEE standards as noted below.

Required surge tests are documented in IEEE Std C37.90.1TM-2002¹. Standardized test waveforms that are representative of surges observed and measured in actual installations are applied to the terminals of the system. The relay or relay system must be able to withstand the applied surges without damage to components and without operating incorrectly.

Required susceptibility tests are documented in IEEE Std C37.90.2TM-1995. The tests establish a method to evaluate the susceptibility of the relay under test to single frequency electromagnetic fields in the radio frequency domain, such as those generated by portable or mobile radio transceivers.

Required electrostatic discharge tests are documented in IEEE Std C37.90.3TM-2001. Generators which that produce a standard waveform are used to apply discharges to conductive and non-conductive points on equipment under test. The test is performed to confirm that relays and relay systems will not misoperate or be damaged when installed, energized, and/or subjected to a specified electrostatic discharge.

1.1 Scope

This standard specifies standard service conditions, standard ratings, performance requirements, and testing requirements for relays and relay systems used to protect and control power apparatus. A relay system may include computer interface equipment and/or communications interface equipment, such as a carrier transmitter/receiver or audio tone equipment. It does not cover relays designed primarily for industrial control, for switching communication or other low-level signals, or any other equipment not intended for control of power apparatus.

¹ Information about the documents referenced in this clause can be found in Annex A.